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## Peculiarities of transport mechanism of stretched polyaniline in temperature range from 100 K to 350 K

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I-V and  $\sigma$ -T characteristics and conductivity versus applied shift dependences of In-PANI-In structures with emeraldine was investigated. The temperature characteristics had constant slope in the range from 160 K to 250 K under various voltages. This determined the activation energy of about 0.23 eV. The behaviour  $I \sim V^{5/4}$  was recognized, which can be evidence of the hopping conductivity. The anomalous effect of conductivity enhance with stretch increase at low voltages is conditioned by the prevalence of increase of cross part of conductivity over decrease of longitudinal one at hopping conductivity.

**Keywords:** Polyaniline; Transport mechanism; I-V characteristic; Differential treatment.

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### I. Introduction

The investigation of properties of electroconducting polyaniline (PANI) are intensive up to date [1,2]. In spite of achievements in this field there is the interest yet to research the electrophysical phenomena including peculiarities of conductivity in structures on the base of electroconducting polymers in general [3,4] and polyaniline in particular [5,6]. One of the methods for conditions changing for charge flow is the stretching both during sample preparation and after one [7,8]. The goal of the present paper is to investigate the peculiarities of charge flow in the In-PANI-In structures by the differential approach [9,10].

### II. Experimental

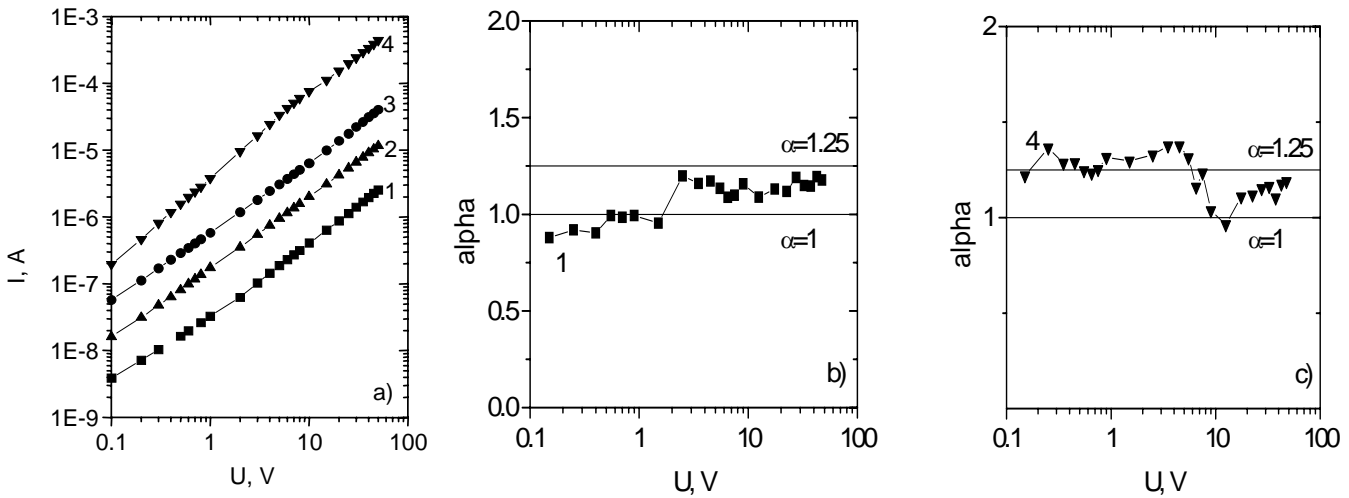
Emeraldine polyaniline has been deposited on the microporous nylon-6 membranes by the standard technique and has been doped in

HClO<sub>4</sub>. The In contacts have been thermally deposited in vacuum. The intercontact length was 1.5 mm. The steady state I-V and temperature characteristics of In-PANI-In structures were measured using the automatized tester 14 TCS-100 and processed by the differential method [9]. This method is based on the determination of dimensionless differential slope,  $\alpha = d(\lg y)/d(\lg x)$ , of the theoretical or experimental characteristics under investigation. With such definition a range of constancy of the  $\alpha(x)$  corresponds to the part of y-x dependencies characterized by the power behavior ( $y \sim x_\alpha$ ).

### III. Results and discussion

The I-V characteristics of In-PANI-In structures under investigation and differential slope of some of them are shown in Fig. 1.

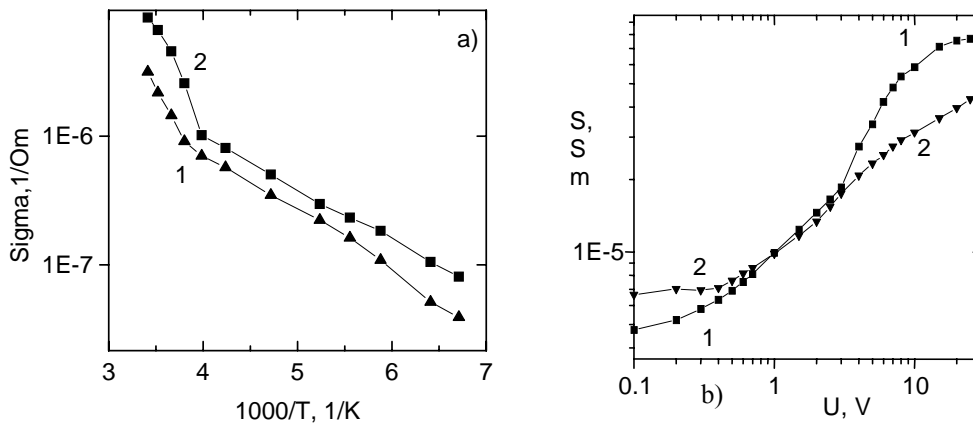
The temperature dependence of conductivity



**Fig.1.** I-V characteristics of In-PANI-In structure at various temperatures: 1 - 153 K; 2 – 184 K; 3 – 240 K; 4 - 294 K (a) and differential slope of 1 (b) and 4 (c) curves.

and conductivity versus shift are shown in Fig. 2. The I-V characteristics have not been changed dramatically (Fig. 1a) and only

differential method allowed underline the fine changing of curves behaviour (Figs. 1b,c).



**Fig.2.** (a) – temperature characteristics of In-PANI-In structure at 0.1 V (1) and 50 V (2) and (b) – conductivity versus shift without (1) and with longitudinal stretch 40 % (2).

From Figs. 1b,c we can see characteristic range with  $\alpha=1.25$ . Such  $\alpha$  value can not be explained by the bimolecular recombination (R) in the structure, when the minority (n) and majority (p) carriers of charge are equal, another way,  $R = \gamma np = \gamma p^2$ , where  $\gamma$  is recombination

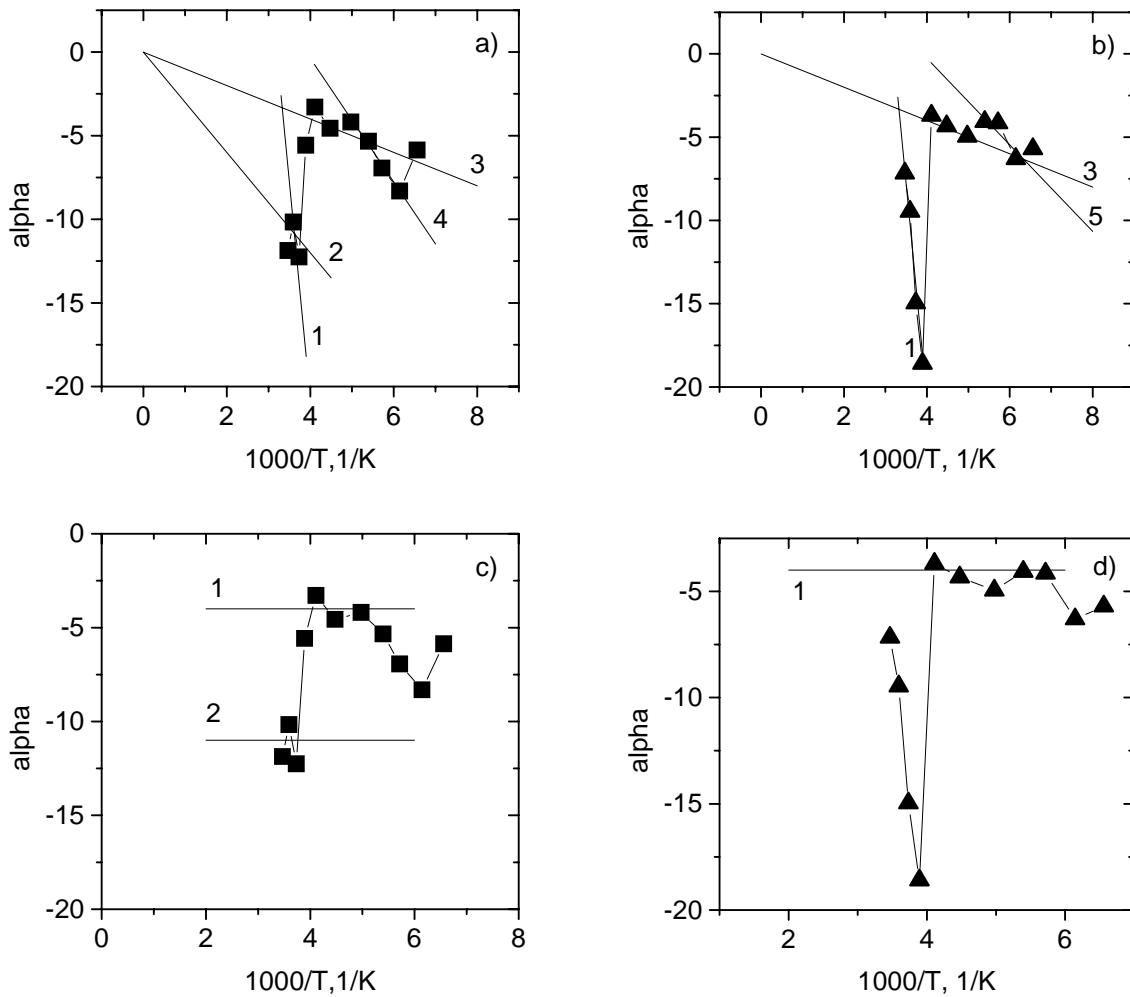
coefficient [10, 11]. Note, that at low temperatures the  $I \sim V^{5/4}$  region goes after Ohm's law whereas at room temperatures it dominates in all bias range. This evidences about carriers injection promotion with increase of temperature. While the injection behaviour

entirely differs from one in crystalline solid state [12].

To clarify the transport mechanism in structures under investigation temperature characteristics and effect of strength were used. Fig. 3 represents the differential slope of temperature characteristics for low and high biases. One can see that the temperature characteristics both in the case of  $V=0.1$  V and  $V=50$  V (Fig. 2a, Figs. 3a,b) have constant slope in the range from 160 K to 250 K. This gives the activation energy of about 0.23 eV. Approximation of this range ( $\sigma \sim \exp[-(1000/T)]$ , line 3) does not be changed with bias. In our opinion the results of Fig. 3 are more close to intersoliton hopping [12] which predicted the steady state conductivity on

temperature in the form  $\sigma \sim T^\alpha$ , where  $\alpha \sim 13$ . In Fig. 3c we have  $\alpha \sim 11 \pm 2$ . S.Kivelson noted [13] that temperature dependence of steady state conductivity can be described good both by  $\sigma \sim T^\alpha$  and  $\sigma \sim \sigma_0 \exp[-(T_0/T)^{1/4}]$ . Last approximation appropriate to the hopping model with changeable length between states localized in the forbidden gap. Really, from Figs. 3a,c and 3b,d one can see that both approximations can describe experimental  $\alpha(1/T)$ .

The unusual stretch-independent behaviour of conductivity has been recognised at middle voltages range of 1 V ... 4 V under stretching (see Fig. 2b) whereas at higher voltages the conductivity was decreased under stretching as



**Fig.3.** Approximation of the differential slope  $\alpha(1/T)$  of temperature characteristic for In-PANI-In structure at 0.1 V (a,c) and 50 V (b,d) in the form:  
 For (a), (b):  $-26(1000/T-3.2)$  (line 1);  $-(3000/T)$  (line 2);  $-(1000/T)$  (line 3);  
 $-3.7(1000/T-3.9)$  (line 4);  $-2.6(1000/T-3.9)$  (line 5) and  
 for (c), (d):  $-(1000/T)^4$  (line 1);  $-(1000/T)^{11}$  (line 2).

usually. At lower voltages the conductivity was increased under stretching. The equation for mobility  $\mu$  can be written as

$$\mu = fa^2 eN(kt)^2 \exp(-E_s/kT)/h^3 \omega^2,$$

where  $f$  is average cosine between hopping direction and electric field vector,  $a$  is intermolecular length,  $N_s$  is quantity of neighbouring next molecule,  $\omega$  is frequency of activation complex vibration,  $E_s$  is barrier energy. In this case the cross part of conductivity prevails the decrease of longitudinal one at hopping conductivity.

#### IV. Conclusion

The investigation of I-V and temperature characteristics and conductivity versus applied shift dependences in In-PANI-In structure have been shown that the regime of hopping conductivity with  $I^{5/4}$  takes place. The anomalous effect of conductivity enhance with stretch increase at low voltages is conditioned by the prevalence of increase of cross part of conductivity over decrease of longitudinal one at hopping conductivity. The activation energy of about 0.23 eV was determined.

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### Особливості механізмів переносу в поздовжньому поліаніліні в діапазоні температур від 100К до 350К

Досліджено вольт-амперні та температурні характеристики, а також провідність в залежності від прикладеної напруги структур In-PANI-In із емеральдиновим поліаналіном. Температурні характеристики мали постійний нахил в діапазоні температур від 160 К до 250 К при різних прикладених напругах. Це обумовлено величиною енергії активації 0.23 еВ. Визначена залежність  $I \sim V^{5/4}$ , яка може бути пов'язана із стрибковою провідністю. Аномальна поведінка зростання провідності із збільшенням розтягування при низьких напругах обумовлена переваженням підвищення поперечної складової провідності над поздовжньою при стрибковій провідності.